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| Notice of References Cited | Application/Control No. 10/707,895 | Applicant(s)/Patent Under Reexamination TSIRLINE ET AL. | |
| | Examiner Uyen-Chau N. Le | Art Unit 2876 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-5,294,931 A | 03-1994 | Meier, Herbert | 342/44 |
| * | B | US-5,587,578 A | 12-1996 | Serra, Didier | 235/492 |
| * | C | US-6,327,972 B1 | 12-2001 | Heredia et al. | 101/35 |
| * | D | US-2002/0003498 A1 | 01-2002 | Wuidart et al. | 343/700.0MS |
| * | E | US-6,409,401 B1 | 06-2002 | Petteruti et al. | 400/88 |
| * | F | US-6,593,853 B1 | 07-2003 | Barrett et al. | 340/572.1 |
| * | G | US-6,857,714 B2 | 02-2005 | Hohberger et al. | 347/2 |
| * | H | US-6,929,412 B1 | 08-2005 | Barrus et al. | 400/76 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------------------|----------------|
| ✓ | N | JP 2003132330 A | 05-2003 | Japan | MURATA, SHINSUKE | G06K 19/077 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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